# International Rectifier

# IRFP150NPbF

HEXFET® Power MOSFET

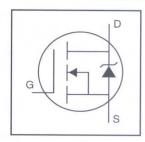
#### Advanced Process Technology

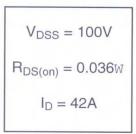
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

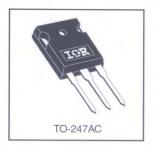
#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.







#### **Absolute Maximum Ratings**

$\begin{array}{llllllllllllllllllllllllllllllllllll$	x. Units
Pulsed Drain Current ⊕ ⊕ 14	
$P_D @T_C = 25^{\circ}C$ Power Dissipation 16 Linear Derating Factor 1. $V_{GS}$ Gate-to-Source Voltage $\pm 2$	Α
Linear Derating Factor 1.  V <sub>GS</sub> Gate-to-Source Voltage ± 2	0
V <sub>GS</sub> Gate-to-Source Voltage ± 2	0 W
	W/°C
Fig. Single Pulse Avalanche Energy@6	20 V
E <sub>AS</sub> Single Pulse Avalanche Energy 2 5 42	0 mJ
AR Avalanche Current ① ⑤	. A
E <sub>AR</sub> Repetitive Avalanche Energy① 16	mJ
dv/dt Peak Diode Recovery dv/dt 3 5.	) V/ns
T <sub>J</sub> Operating Junction and -55 to	+ 175
T <sub>STG</sub> Storage Temperature Range	°C
Soldering Temperature, for 10 seconds 300 (1.6mm	
Mounting torque, 6-32 or M3 srew 10 lbf•in (	1 1Nem)

#### Thermal Resistance

	Parameter	Typ.	Max.	Units
R <sub>0</sub> JC	Junction-to-Case	_	0.95	
Recs	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
R <sub>0JA</sub>	Junction-to-Ambient	_	40	

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# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100	-		V	$V_{GS} = 0V$ , $I_D = 250\mu A$	
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	_	0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>(S)</sup>	
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	-	_	0.036	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 23A ④	
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	_	4.0	٧	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$	
9fs	Forward Transconductance	14	-		S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 22A <sup>⑤</sup>	
			_	25	μА	$V_{DS} = 100V, V_{GS} = 0V$	
DSS	Drain-to-Source Leakage Current	_	_	250	μА	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C	
2	Gate-to-Source Forward Leakage	_		100		$V_{GS} = 20V$	
GSS	Gate-to-Source Reverse Leakage	_		-100	nA	$V_{GS} = -20V$	
Qq	Total Gate Charge	_		110		I <sub>D</sub> = 22A V <sub>DS</sub> = 80V	
Qgs	Gate-to-Source Charge			15	nC		
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	-	-	58		$V_{GS} = 10V$ , See Fig. 6 and 13 $\P$	
t <sub>d(on)</sub>	Turn-On Delay Time	_	11	-		$V_{DD} = 50V$ $I_D = 22A$	
tr	Rise Time		56	_	no		
t <sub>d(off)</sub>	Turn-Off Delay Time	_	45	_	ns	$R_G = 3.6W$	
t <sub>f</sub>	Fall Time	-	40	_		R <sub>D</sub> = 2.9W, See Fig. 10 4 9	
L <sub>D</sub>	Internal Drain Inductance	_	5.0	-	nH	Between lead, 6mm (0.25in.)	
L <sub>S</sub>	Internal Source Inductance		13	_		from package and center of die contact	
Ciss	Input Capacitance	-	1900	-		V <sub>GS</sub> = 0V	
Coss	Output Capacitance	_	450	- i	pF	$V_{DS} = 25V$	
Crss	Reverse Transfer Capacitance		230	-		f = 1.0MHz, See Fig. 5©	

#### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
ls	Continuous Source Current (Body Diode)	_	_	42	A	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①⑤		-	140		integral reverse p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage		_	1.3	V	$T_J = 25^{\circ}C$ , $I_S = 23A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		180	270	ns	$T_J = 25^{\circ}C, I_F = 22A$
Qrr	Reverse RecoveryCharge		1.2	1.8	μC	di/dt = 100A/μs ④ ⑤
ton	Forward Turn-On Time	Intrinsic tum-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub>				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\label{eq:starting} \begin{array}{l} \text{ \ensuremath{\mathbb{Z}}} \text{ Starting } T_J = 25^\circ\text{C}, \ L = 1.7\text{mH} \\ \text{R}_G = 25\text{W}, \ I_{AS} = 22\text{A}. \ \mbox{(See Figure 12)} \end{array}$
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- (5) Uses IRF1310N data and test conditions

# International TOR Rectifier

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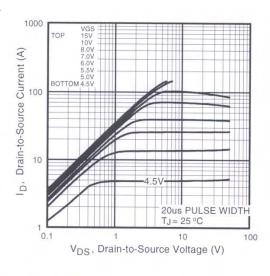


Fig 1. Typical Output Characteristics

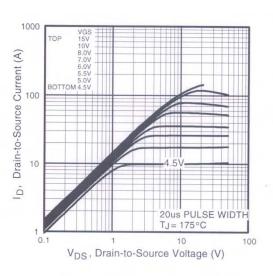


Fig 2. Typical Output Characteristics

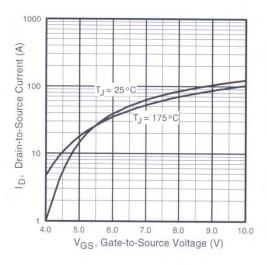


Fig 3. Typical Transfer Characteristics

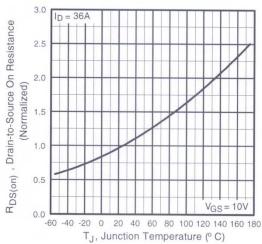


Fig 4. Normalized On-Resistance Vs. Temperature

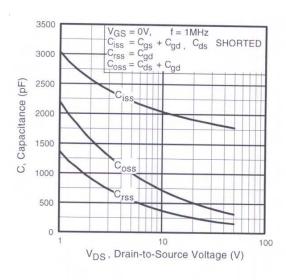
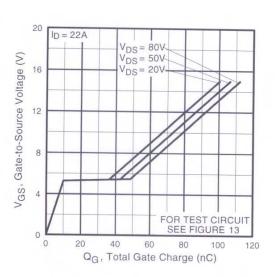


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

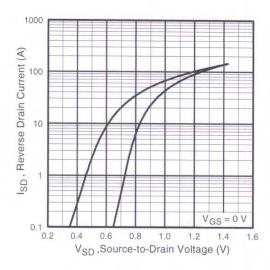


Fig 7. Typical Source-Drain Diode Forward Voltage

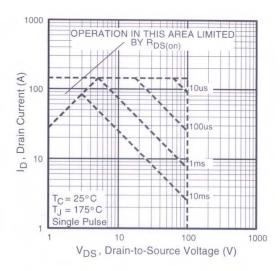


Fig 8. Maximum Safe Operating Area

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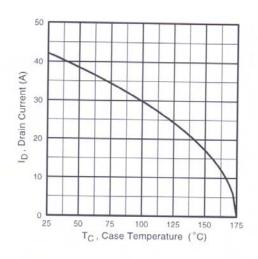


Fig 9. Maximum Drain Current Vs. Case Temperature

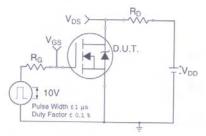


Fig 10a. Switching Time Test Circuit

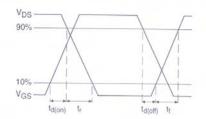


Fig 10b. Switching Time Waveforms

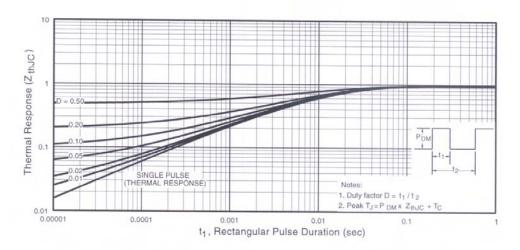


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

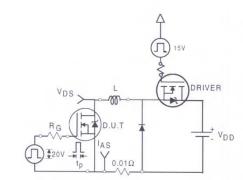


Fig 12a. Unclamped Inductive Test Circuit

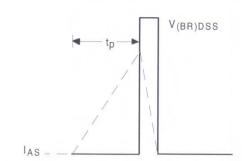


Fig 12b. Unclamped Inductive Waveforms

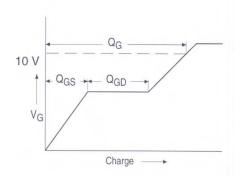


Fig 13a. Basic Gate Charge Waveform

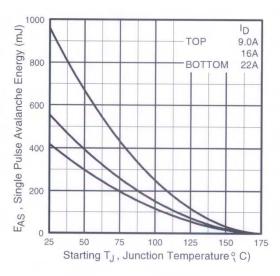


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

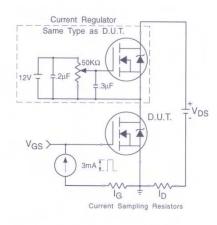
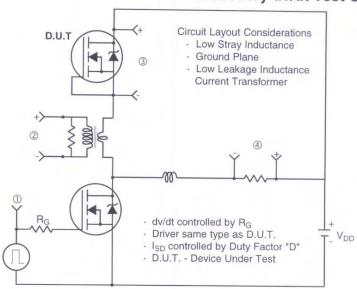
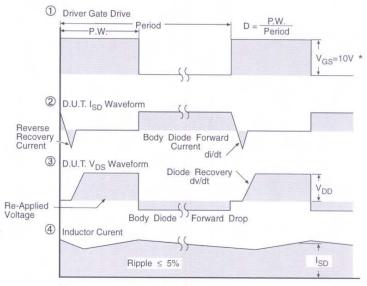


Fig 13b. Gate Charge Test Circuit

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## Peak Diode Recovery dv/dt Test Circuit



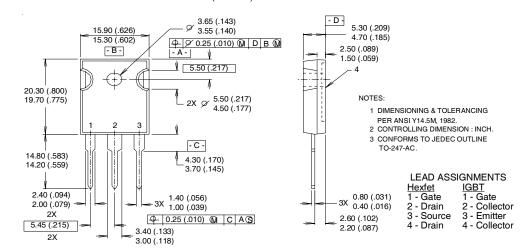


\* V<sub>GS</sub> = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

### TO-247AC Package Outline

Dimensions are shown in millimeters (inches)



## TO-247AC Part Marking Information



Data and specifications subject to change without notice.



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